

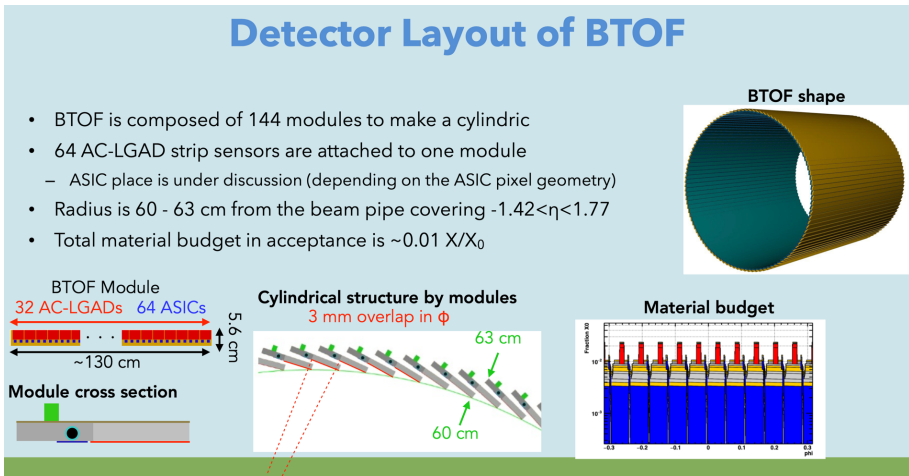
AC-LGAD Progress Report

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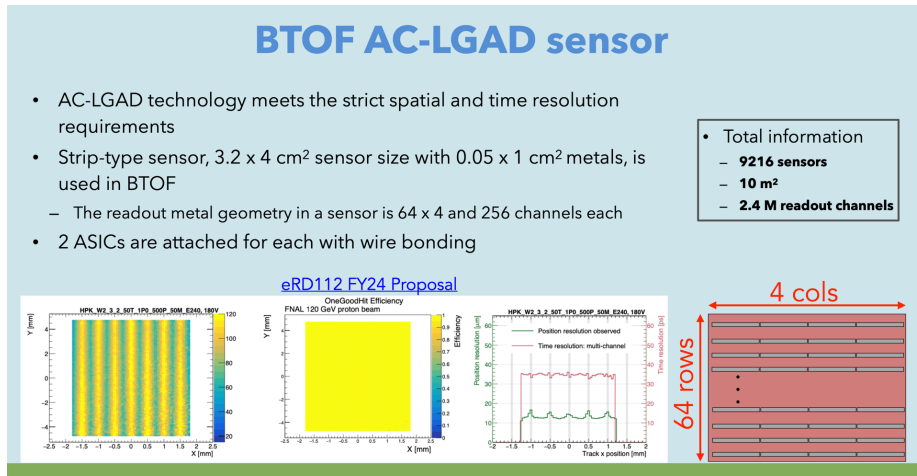
Motivation

- Development for installation in ePIC experimental TOF detector
 - ✓ Achieve ~ 30 ps timing resolution and ~ 30 μm spatial resolution
 - ✓ Study the temperature dependence of sensor performance
 - A change of 1°C results in a change of 1V
 - ✓ To enable accurate performance evaluation in a laboratory system

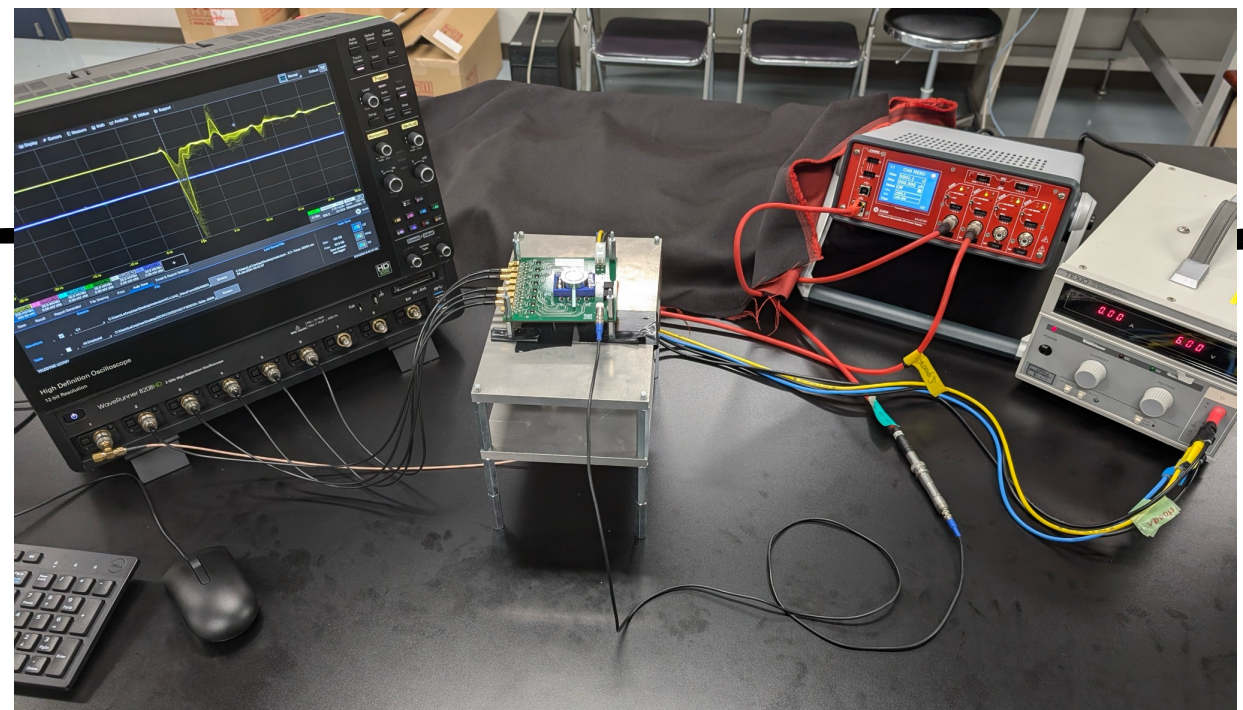


← Yano-san's slide →
 (2024/06/24 EIC-asia meeting)

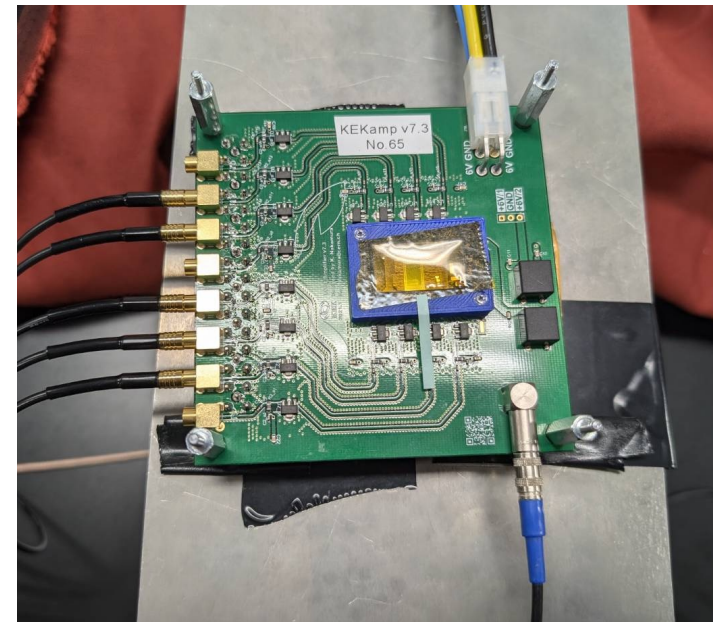
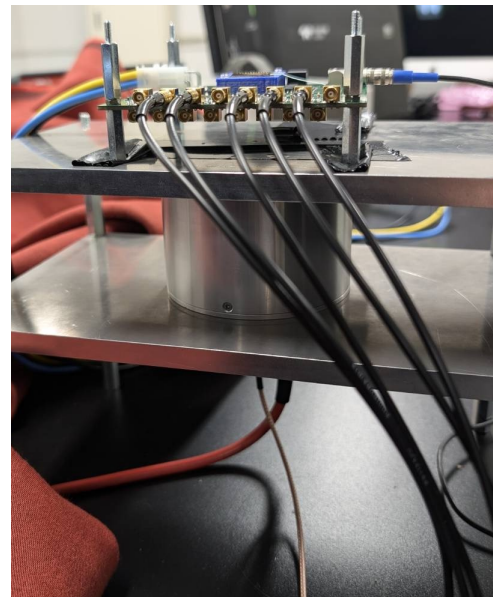
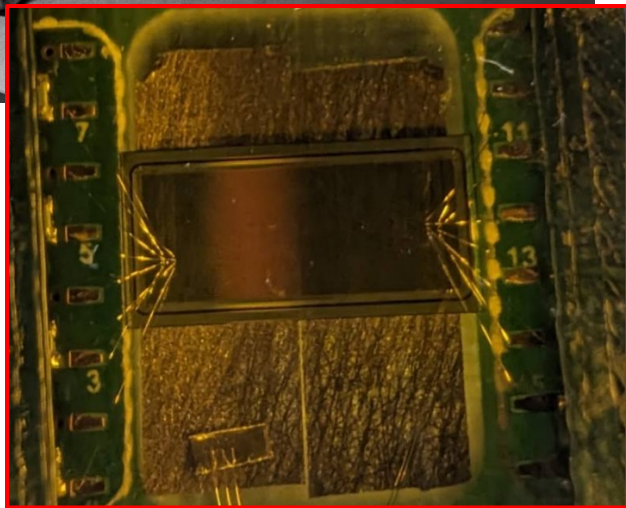
EIC-Japan meeting/K.Matsutani



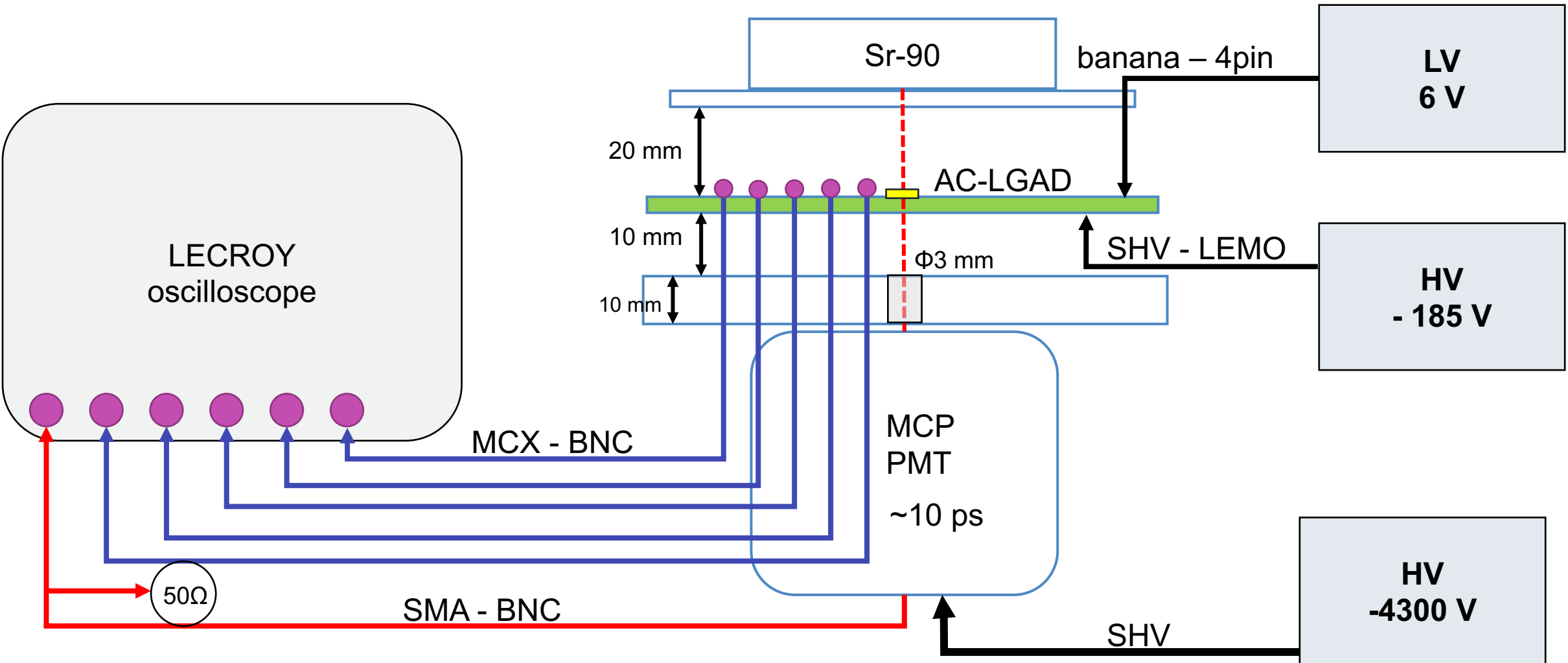
Testbench



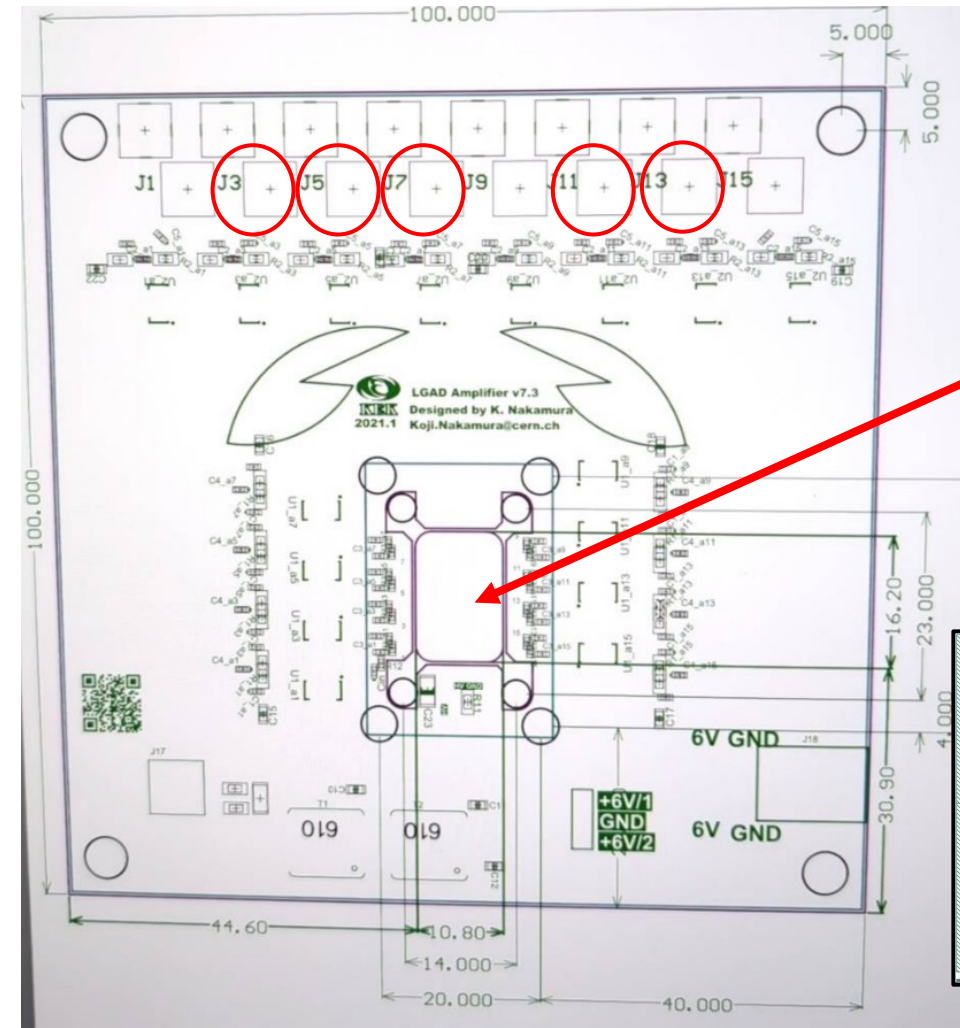
Stripe-type AC-LGAD
from KEK(HPK) →



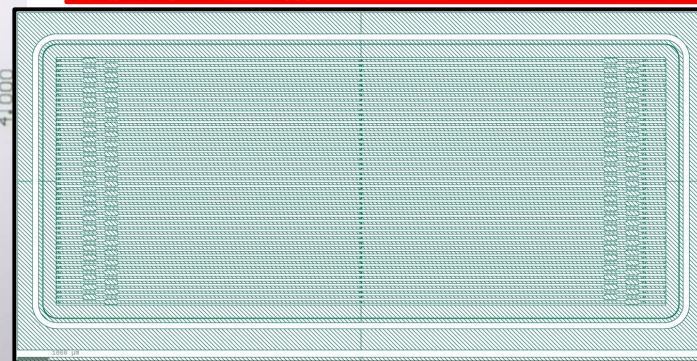
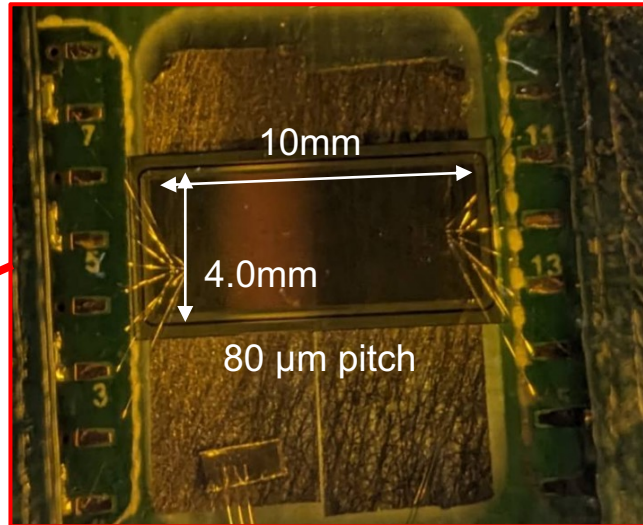
Experiment Setup



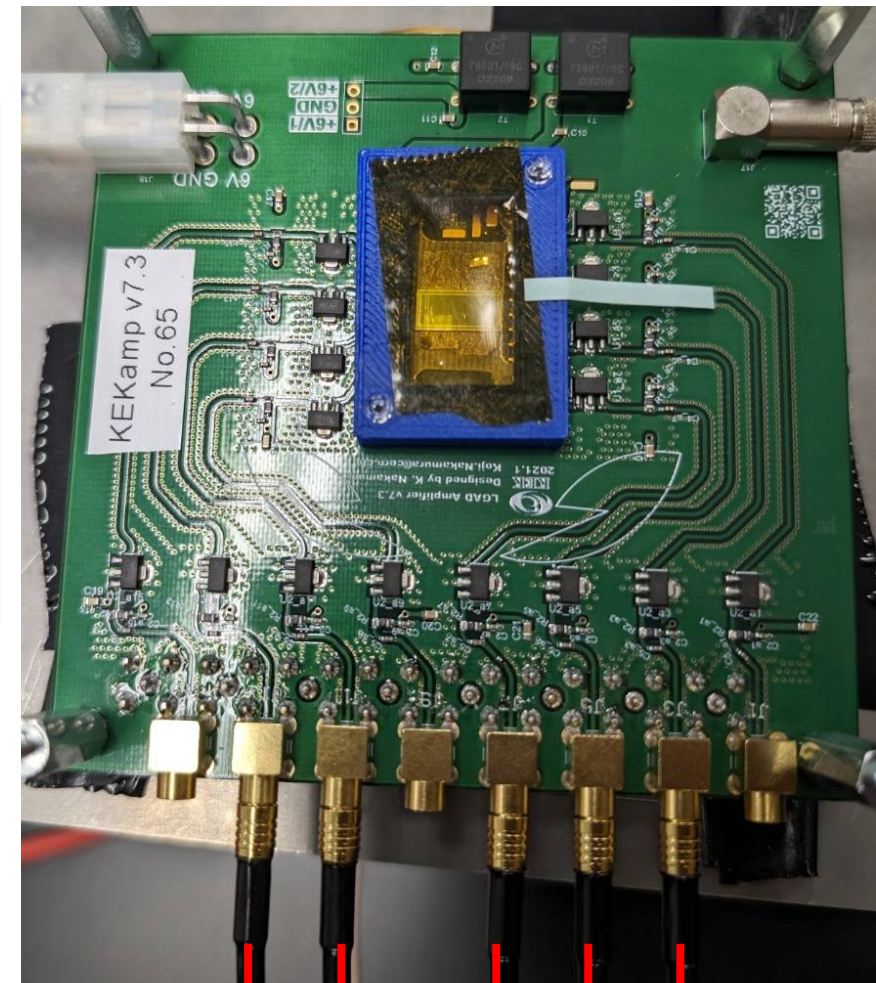
Select AC-LGAD channel



Wire-bonded AC-LGAD



50 stripes, 16 wire-bonded



C6 C5 C4 C3 C2

Current Result

- Bias Voltage dependence
- V-I Correlation
- Checking each channel signal waveform
- Pulse Height Distribution
- Observation of charge sharing
- Discovery of feature of HPK AC-LGAD (Amp board of KEK)

Bias Voltage dependence

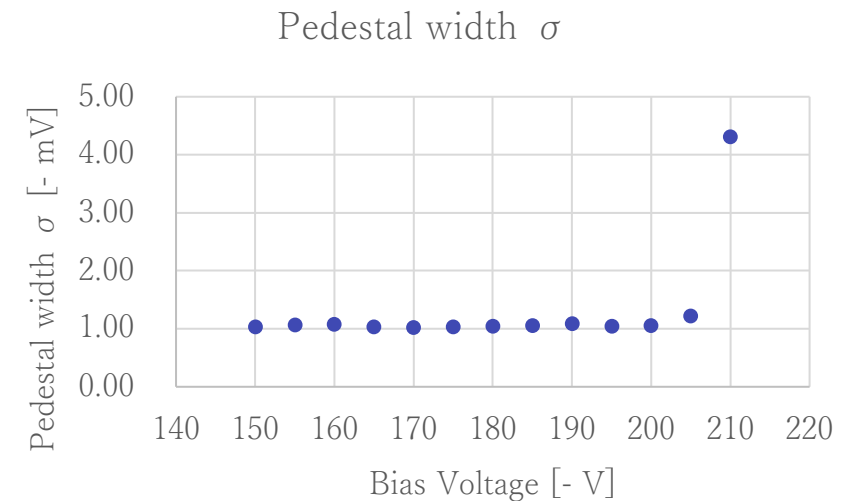
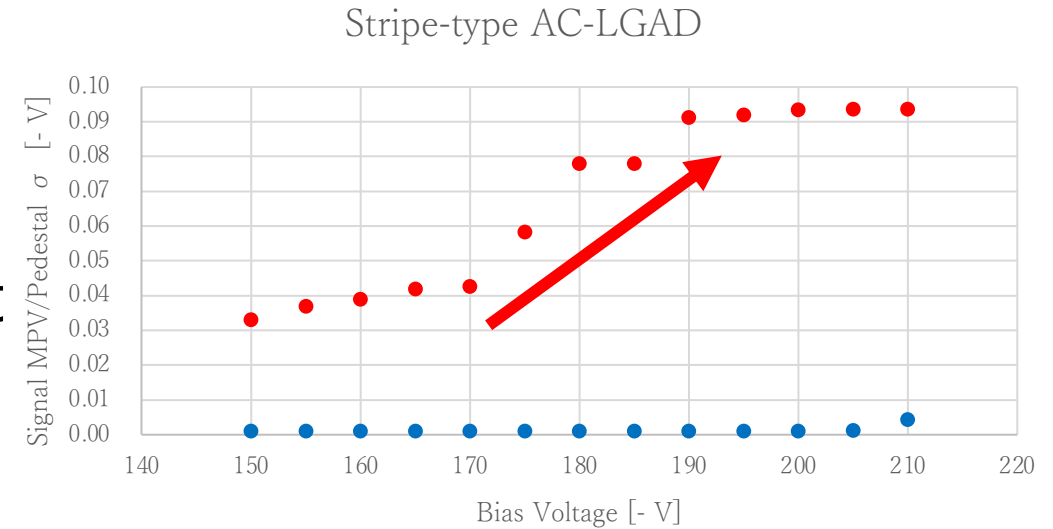
■ Maximum Point Voltage

- ✓ -170V \rightarrow -190V for large voltage increase
- ✓ -190 V and thereafter almost constant value

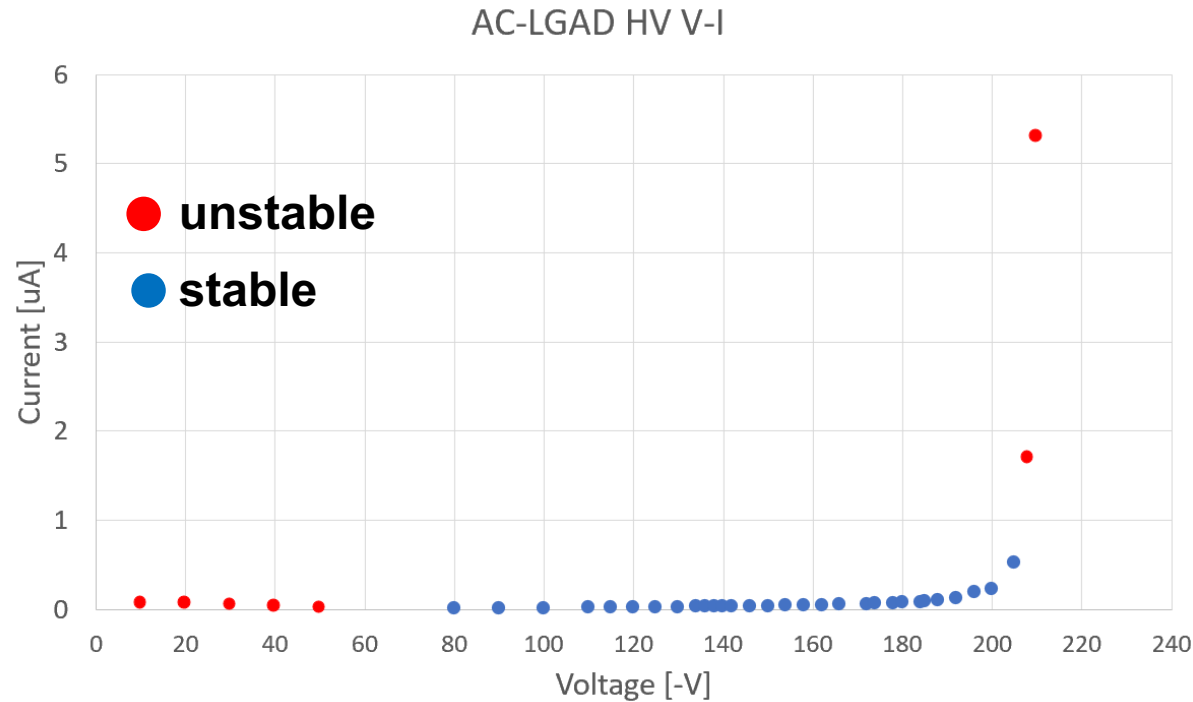
■ Pedestal width σ

- ✓ Basically settled around -1.0 mV
- ✓ Started to increase from -205V, and suddenly became greatly blurred at -210V

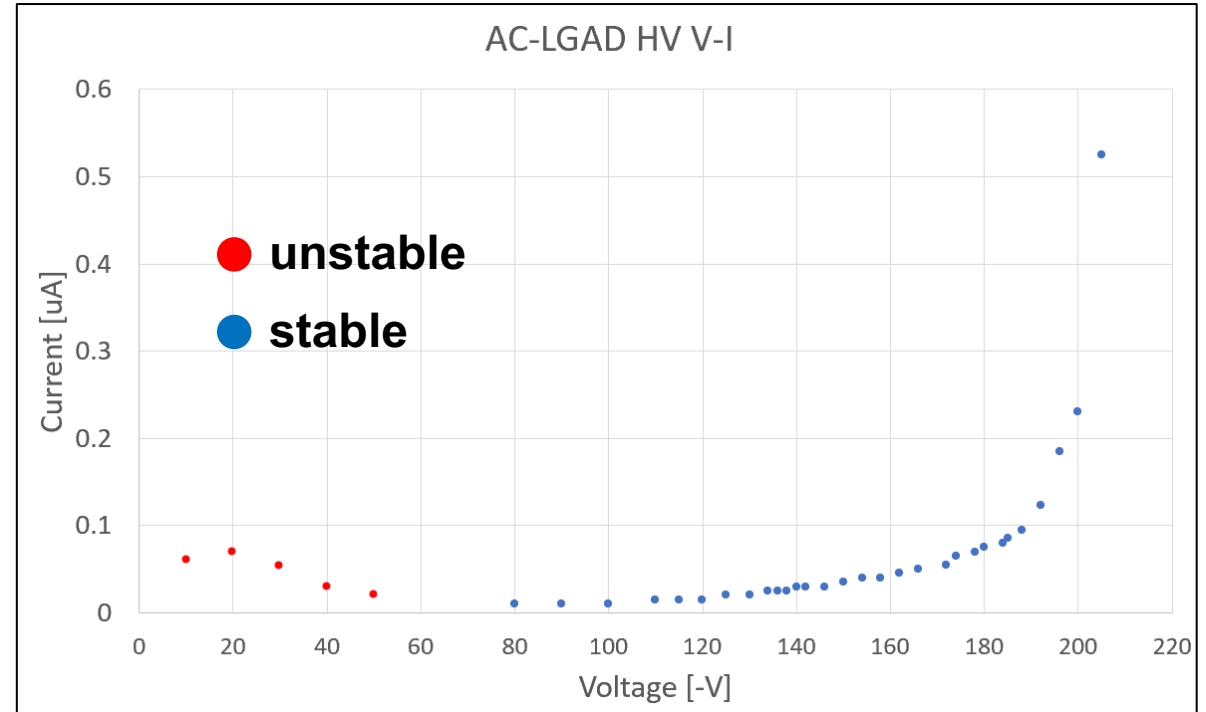
Other status
LV: 5.56V, 0.44A
Trigger: C2, -5.0 mV



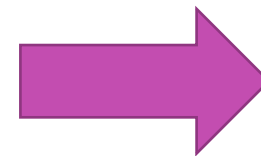
V-I Correlation



Zoom (0V -> -205V)

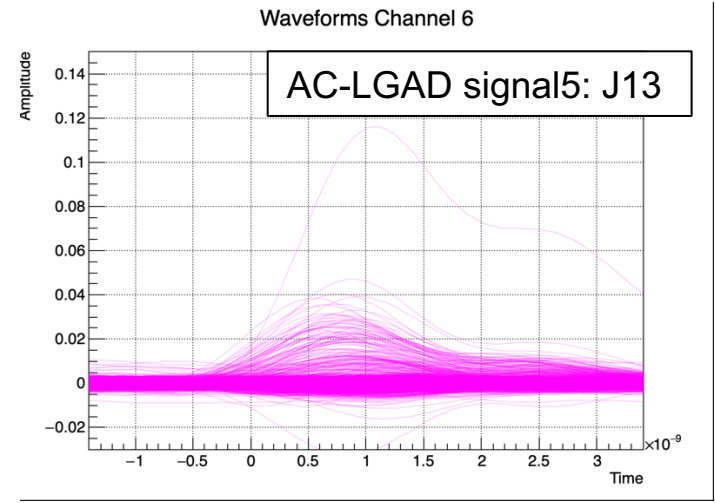
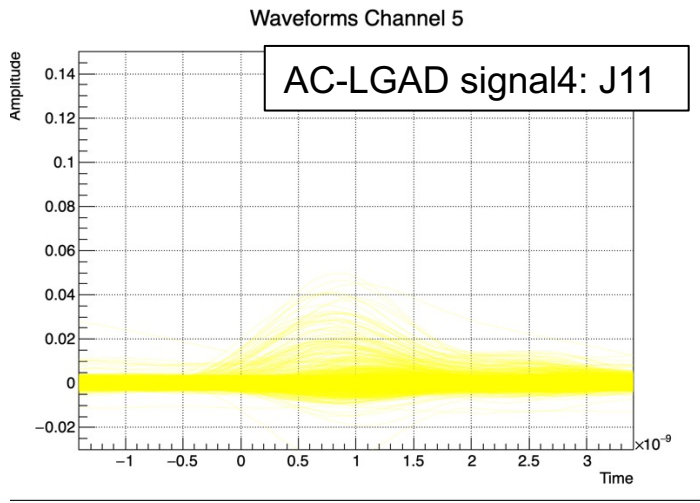
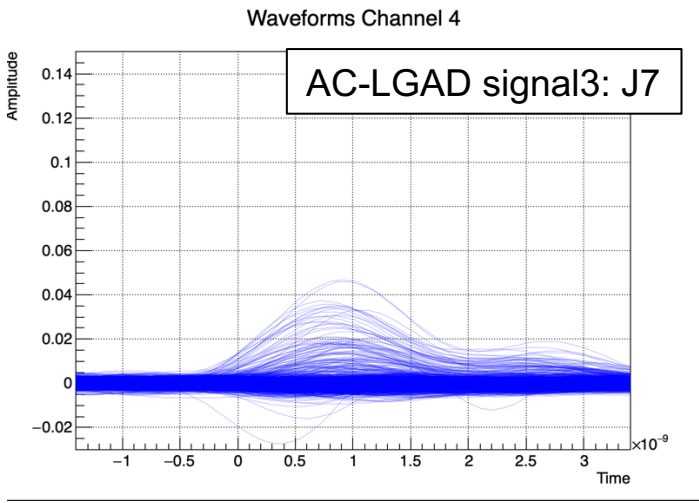
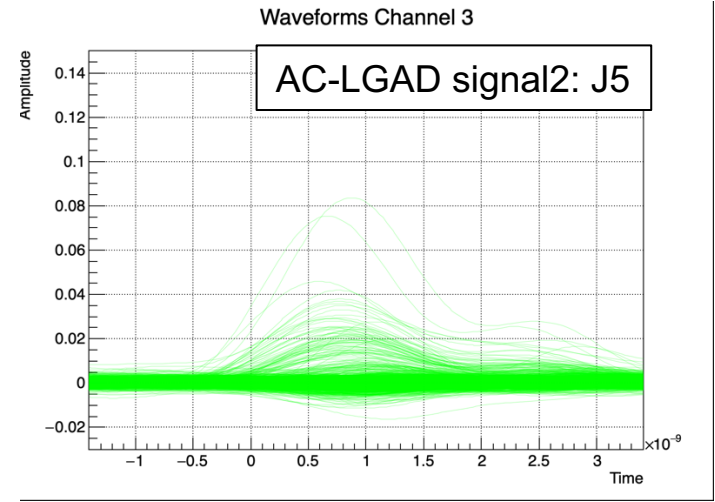
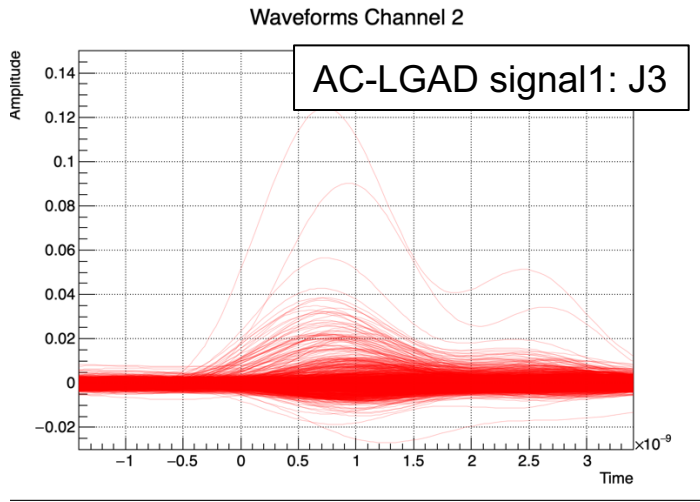
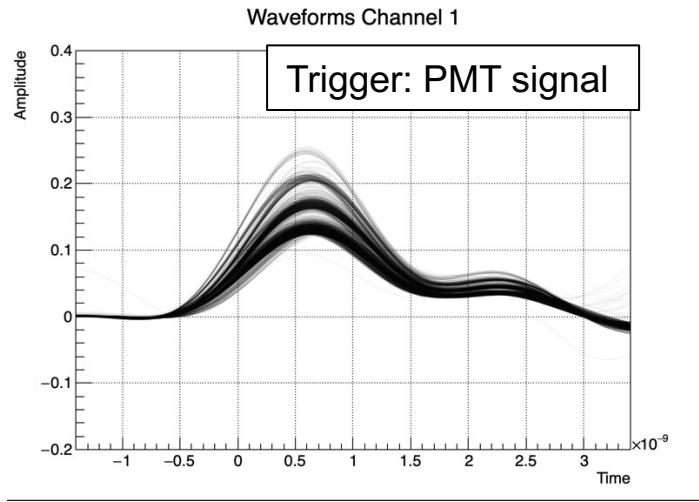


■ Sharply increasing trend after -185V



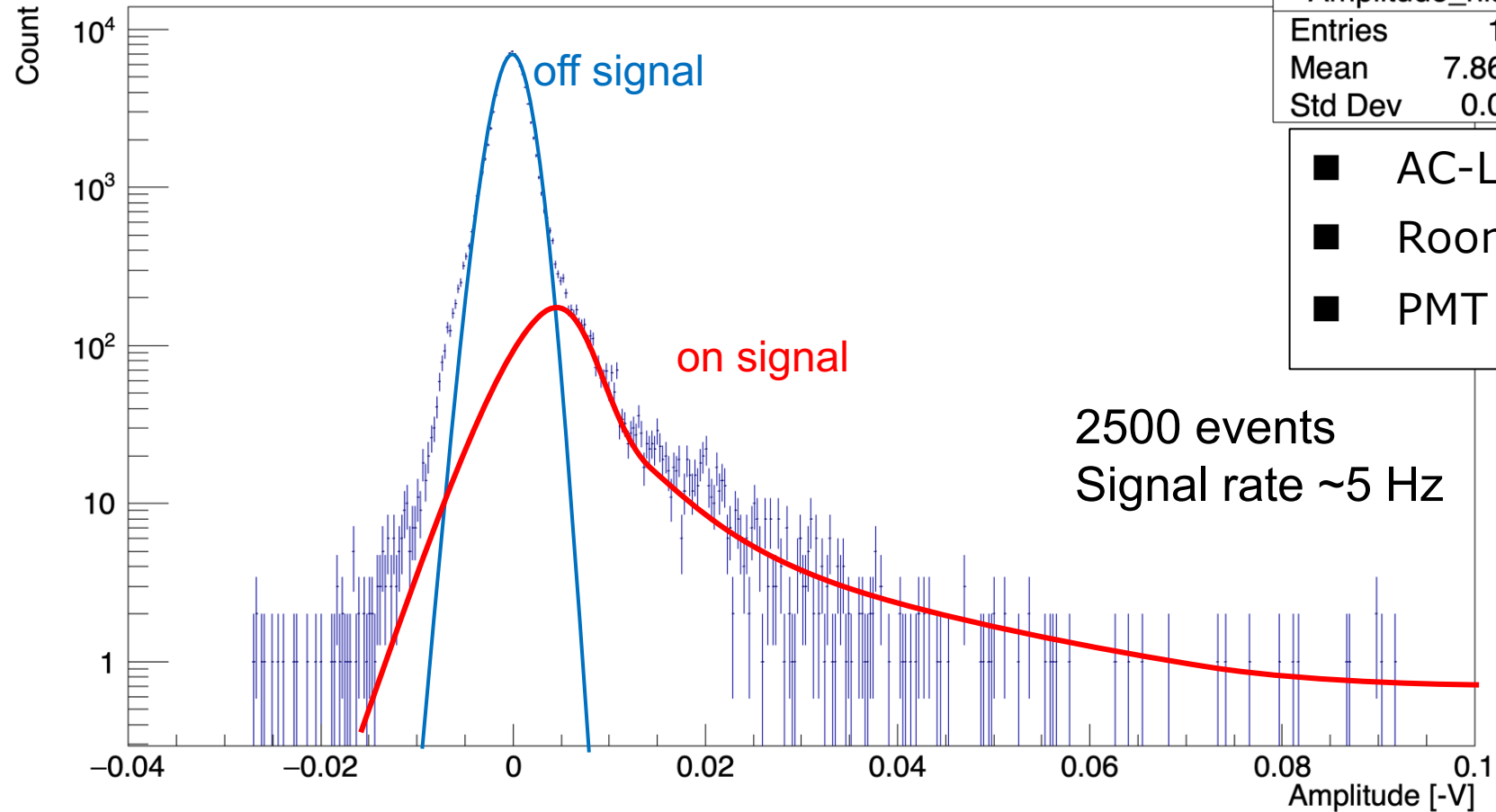
HV optimum value is determined to be -185 V

Each channel waveform HV:-185V, 23°C



Pulse Height Distribution

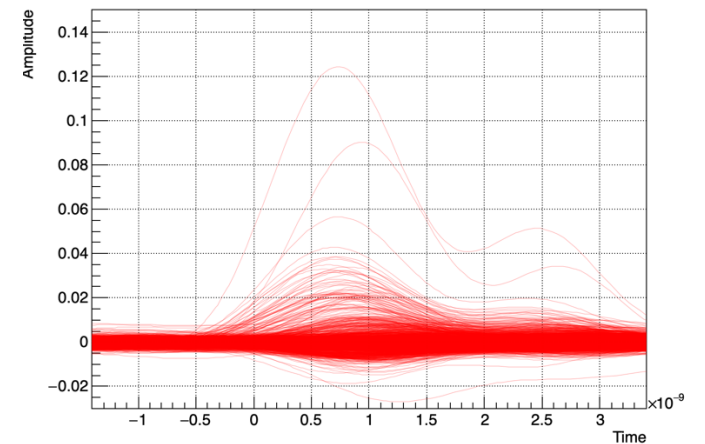
Amplitude Histogram Channel 2



Amplitude_hist_C2	
Entries	104000
Mean	7.864e-05
Std Dev	0.003226

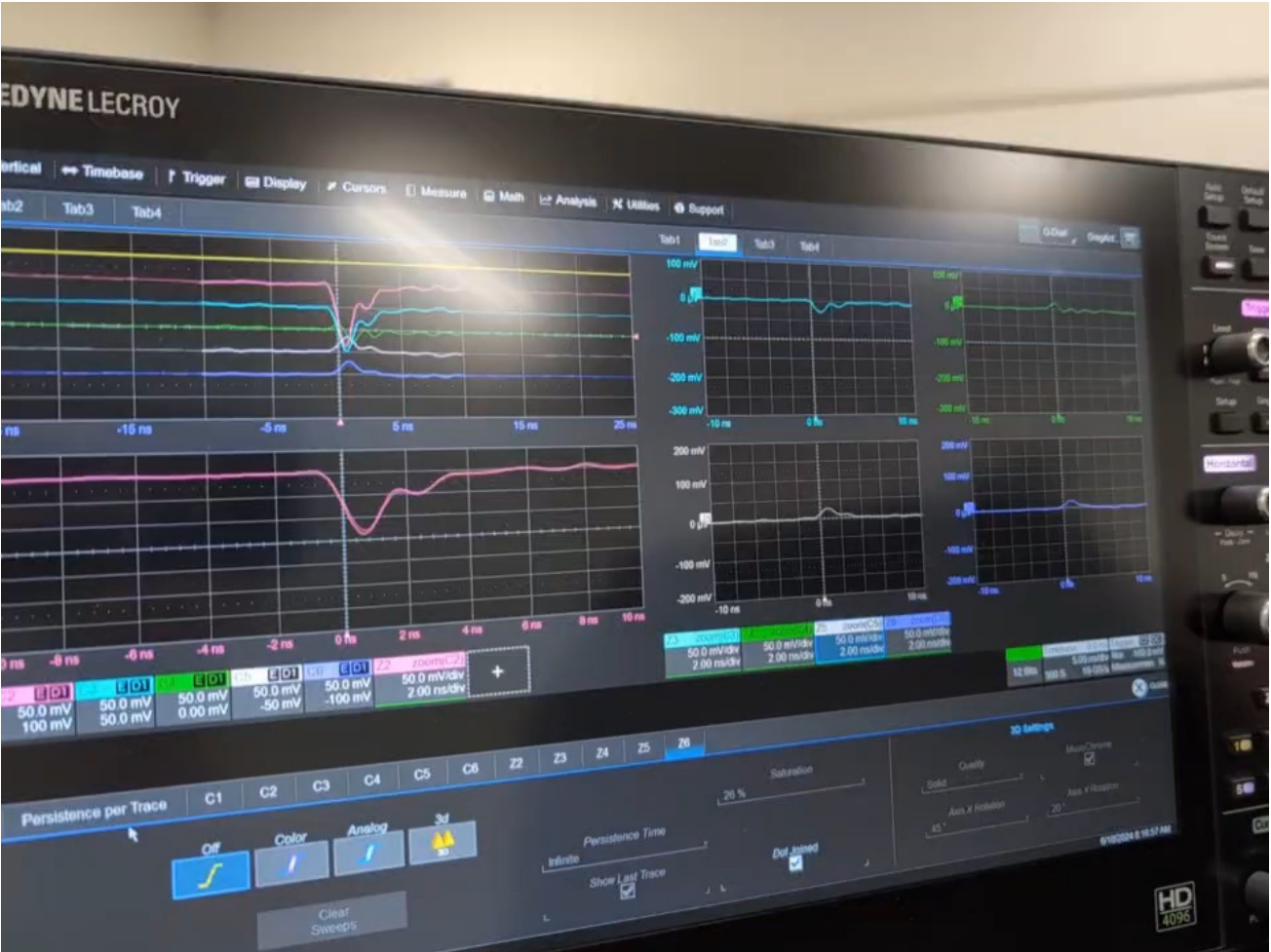
- AC-LGAD HV:-185V
- Room temperature: 23°C
- PMT signal threshold: -100 mV

Waveforms Channel 2



Observation of charge sharing

Movie (trigger: C2 signal)



Trigger signal (PMT)



Trigger signal (PMT)

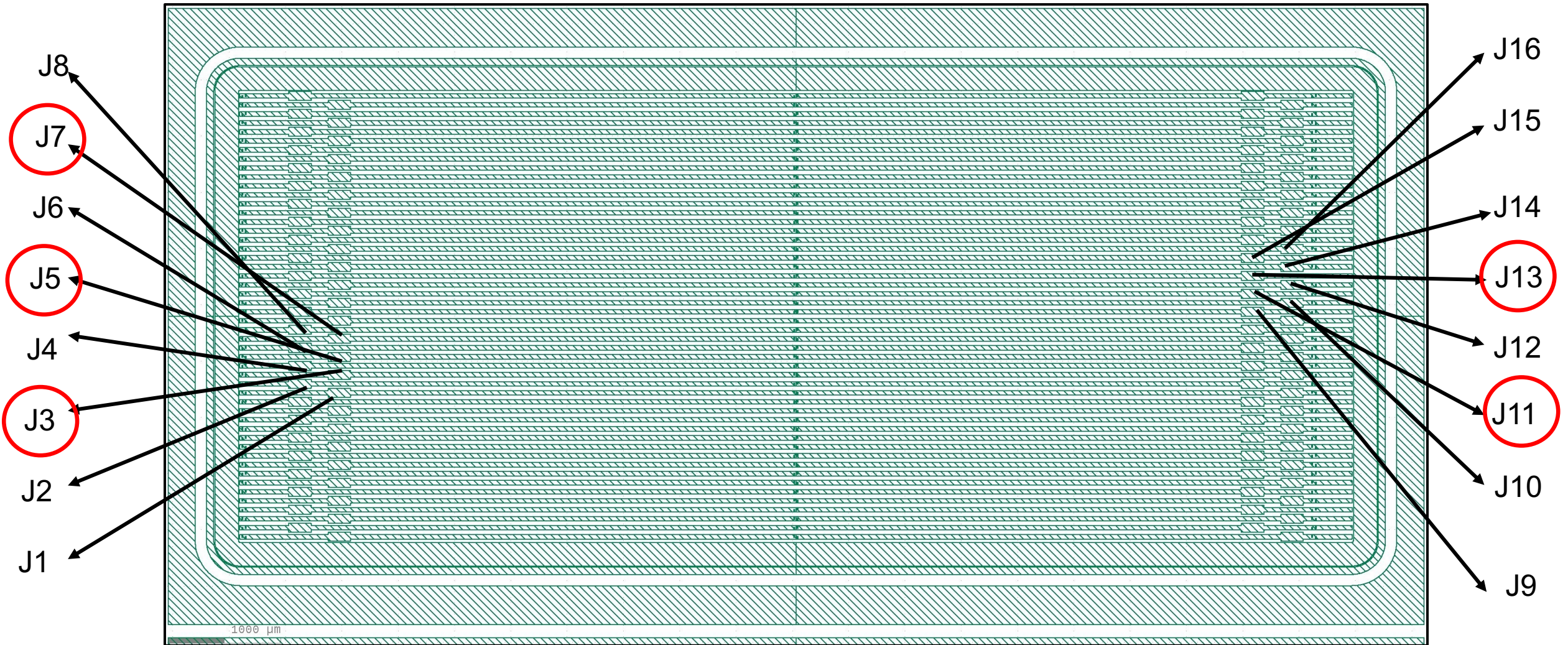


Weirdness of Waveforms

- The waveform of the channel that is wire-bonded on the opposite side to the trigger channel tends to be reserved.
- The reason for this is under investigation

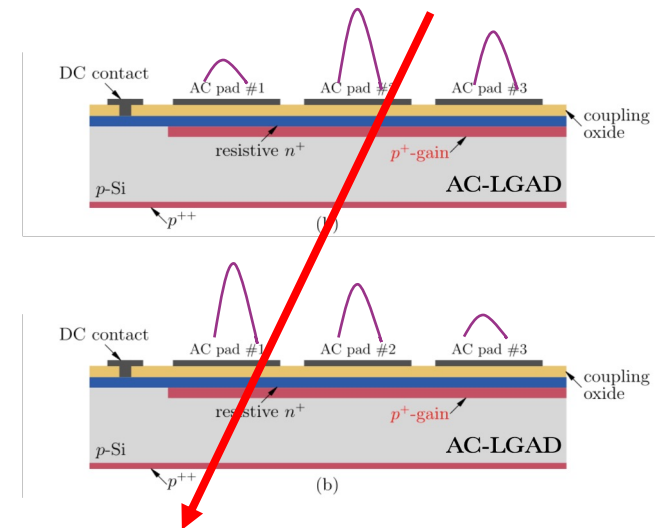


Wire-bonded sensor



Next plan

- Signal Waveform Analysis
 - ✓ Calculate time resolution by reading values
- Measurement of temperature dependence
 - ✓ 1V change at 1°C (AC-LGAD HV)
- Trigger dependence
 - ✓ -100mV or -150 mV on PMT signal
- 10-20 BNL AC-LGADs will arrive
 - ✓ We can measure path length of decay electron



Summary

- Hiroshima Univ. started evaluating the performance of the strip AC-LGAD (from HPK) using a radioactive source.
 - ✓ $0.4 \times 10 \text{ mm}^2$ strips with $80 \text{ }\mu\text{m}$ pitch
- The dependence on bias voltage was evaluated
 - ✓ **The optimum HV is -185V**
- The signals(P/N) are different for each channel (but correlated)
- HU will evaluate the **temperature dependence** and **gain uniformity** of full-size sensor

Reference of this research

- [arXiv:2207.07355](https://arxiv.org/abs/2207.07355)
- <https://tchou.tomonaga.tsukuba.ac.jp/events/20/201130/06.pdf>
- R&D of 4D Detectors with EICROC and AC-LGAD at EIC consolidating a US-Japan Consortium

Backup

Time resolution

$$\sigma_t^2 = \sigma_{tw}^2 + \sigma_j^2 + \sigma_L^2$$

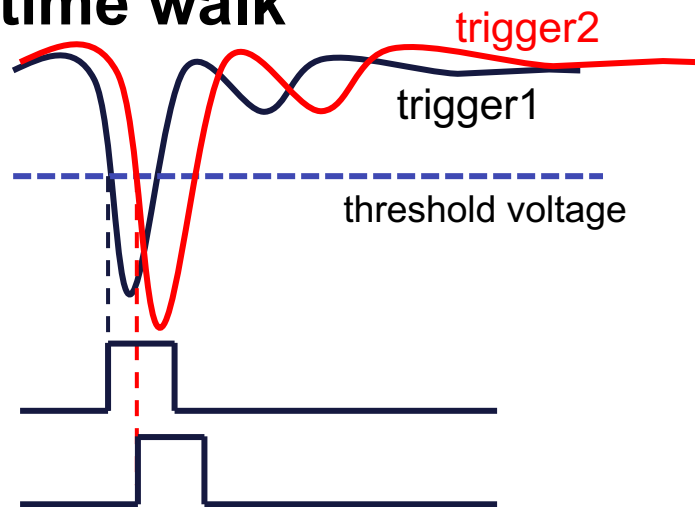
σ_t : time resolution

σ_{tw} : time walk

σ_j : time jitter

σ_L : Landau noise

time walk

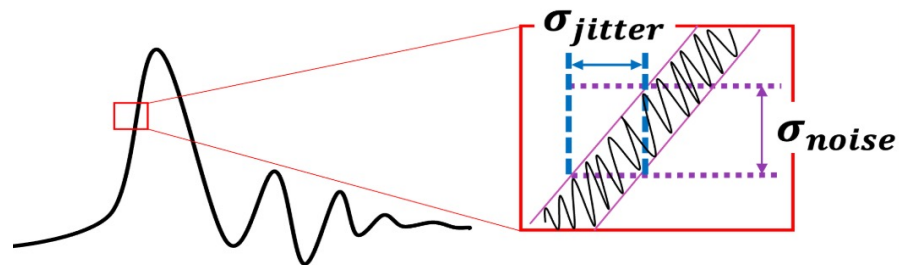


2024/06/26

time jitter

$$\sigma_j = \frac{\sigma_{noise}}{\left| \frac{signal}{t_{rise}} \right|}$$

σ_{noise} : noise width
 t_{rise} : rise time
signal: pulse height

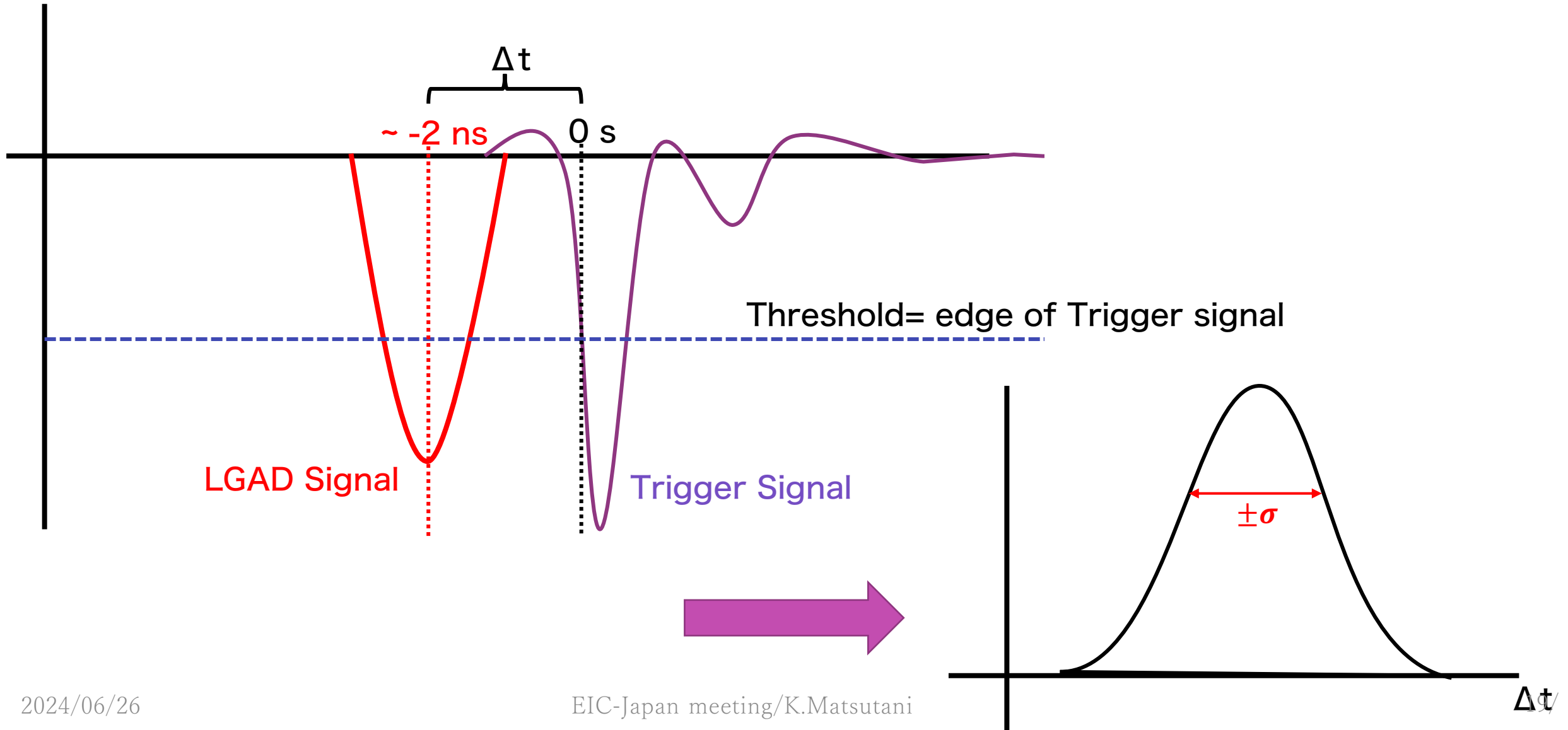


EIC-Japan meeting/K.Matsutani

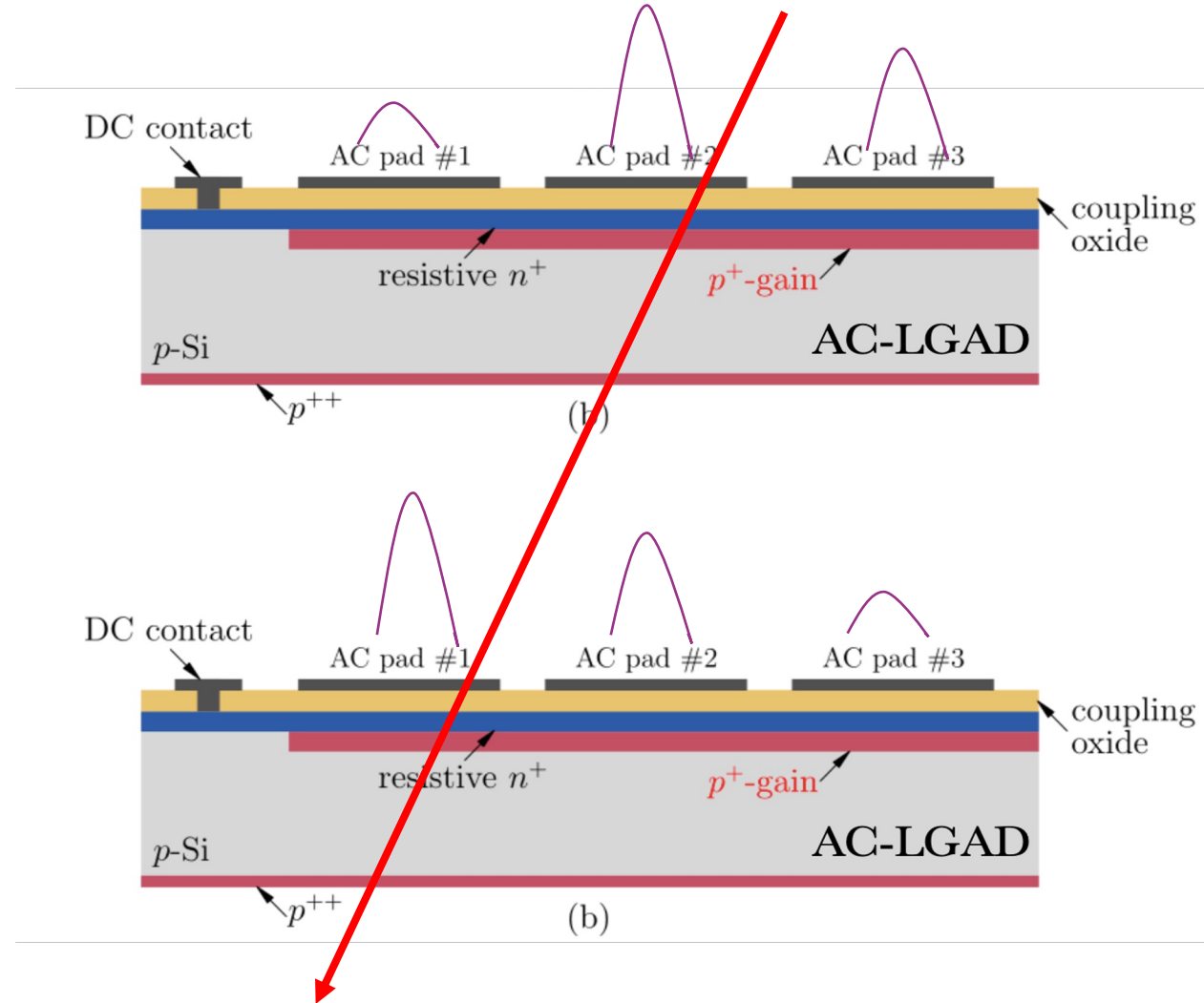
Landau noise

Noise due to statistical distribution in energy deposition by incident electrons.

Time resolution σ measurement



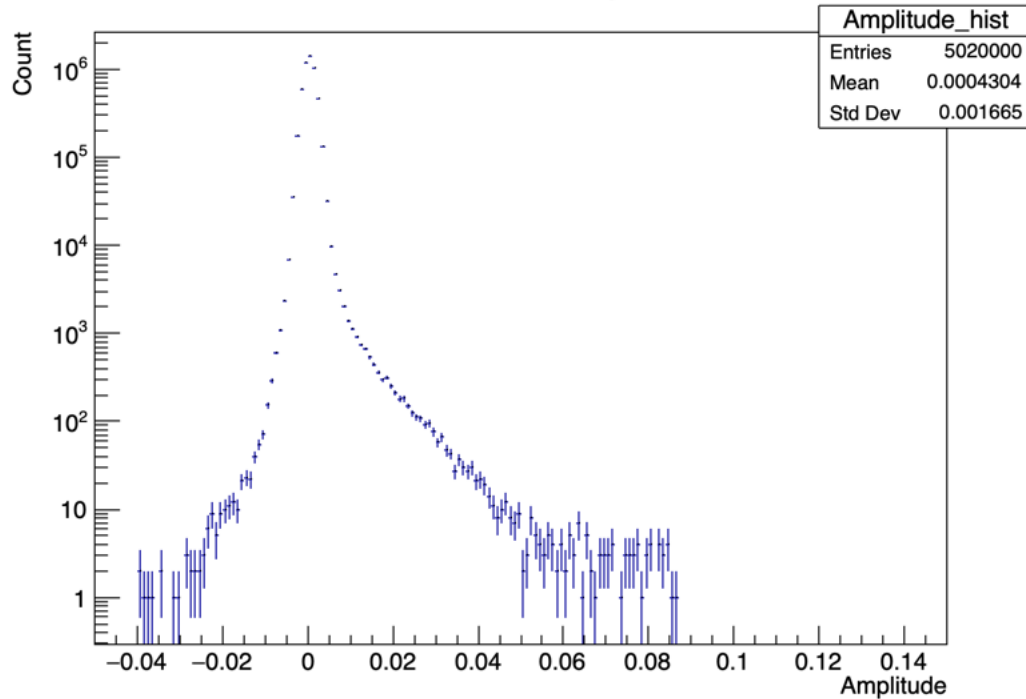
Path length using multi AC-LGADs



Trigger dependence; Bias Voltage: -185 V

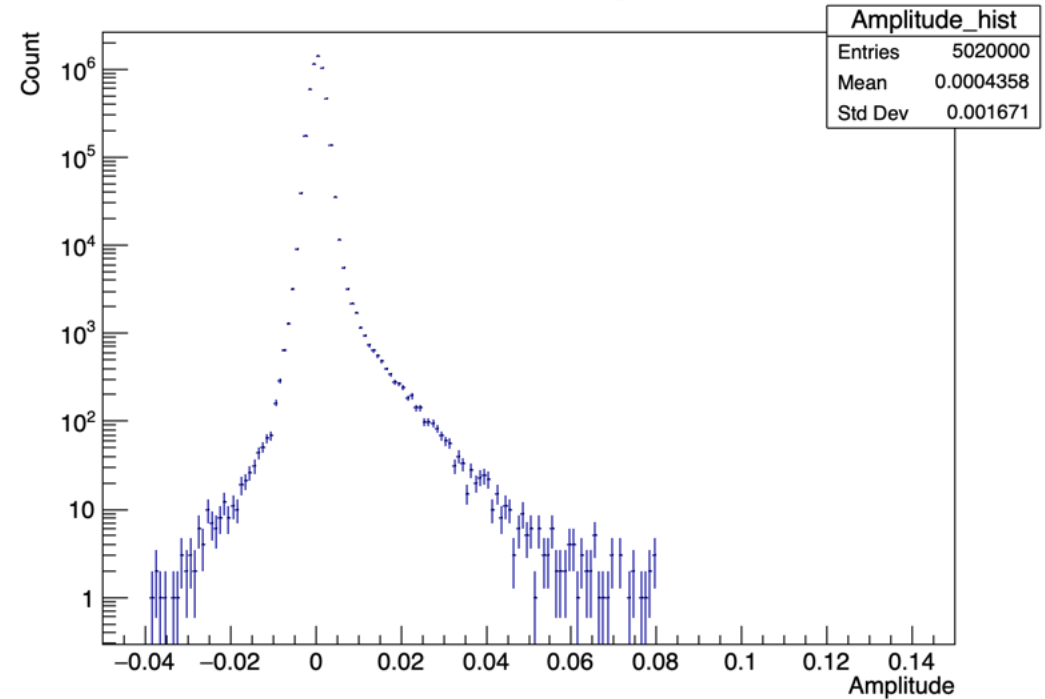
Trigger: -40mV PMT signal

Amplitude Histogram



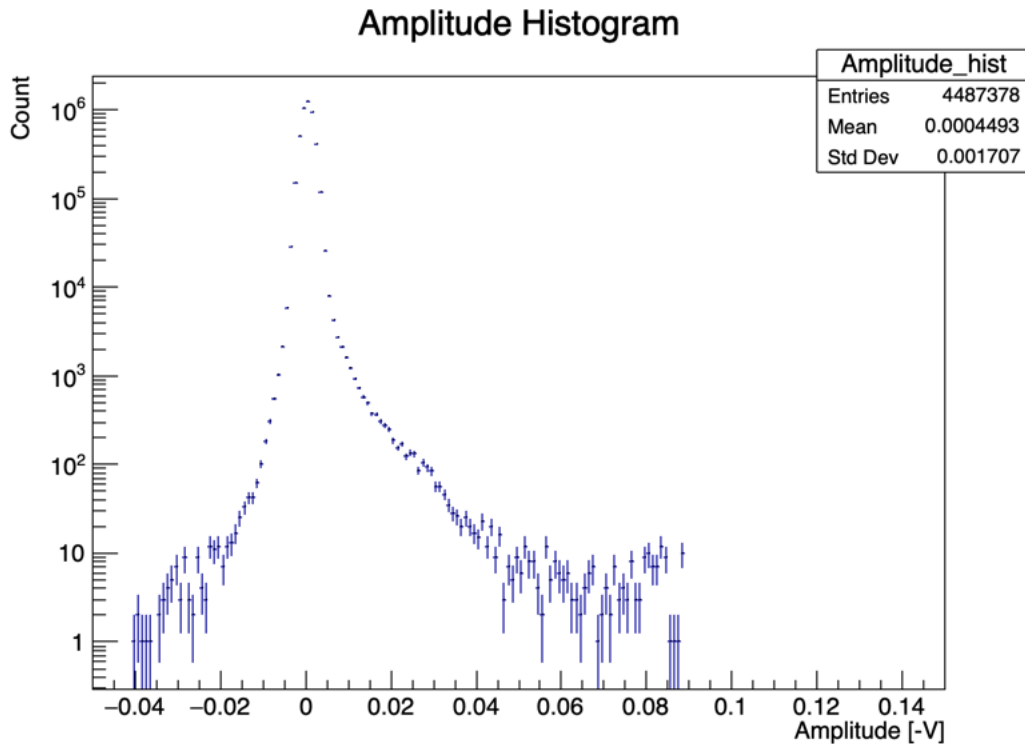
Trigger: -80mV PMT signal

Amplitude Histogram

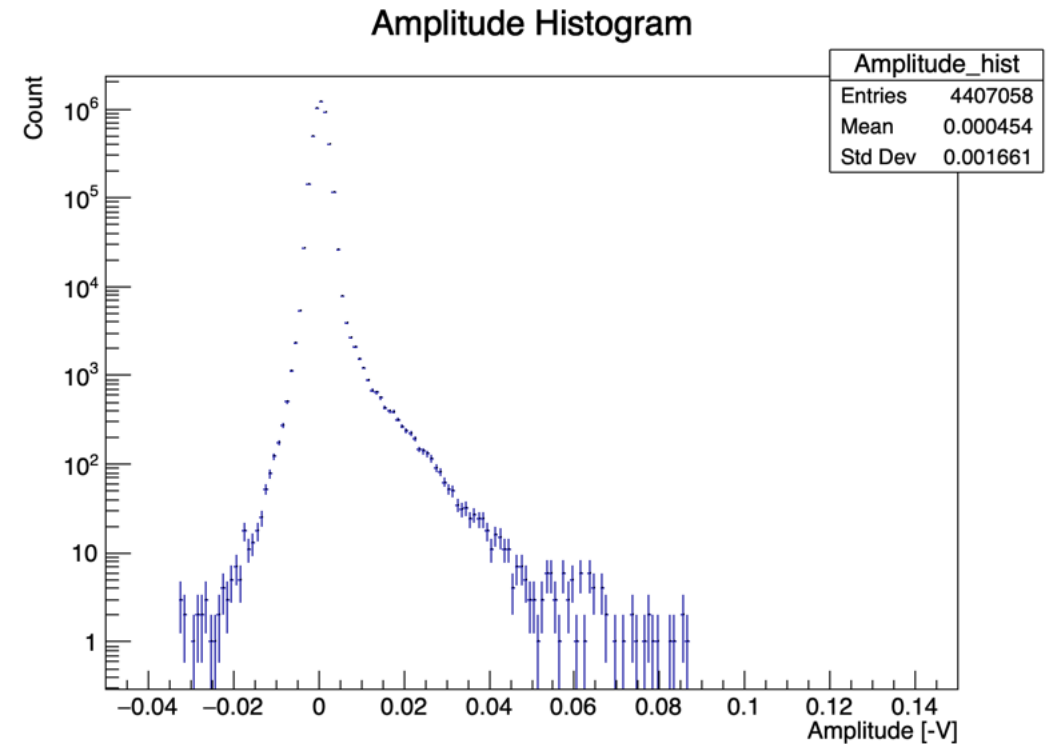


Trigger dependence; Bias Voltage: -185V

Trigger: -100mV PMT signal



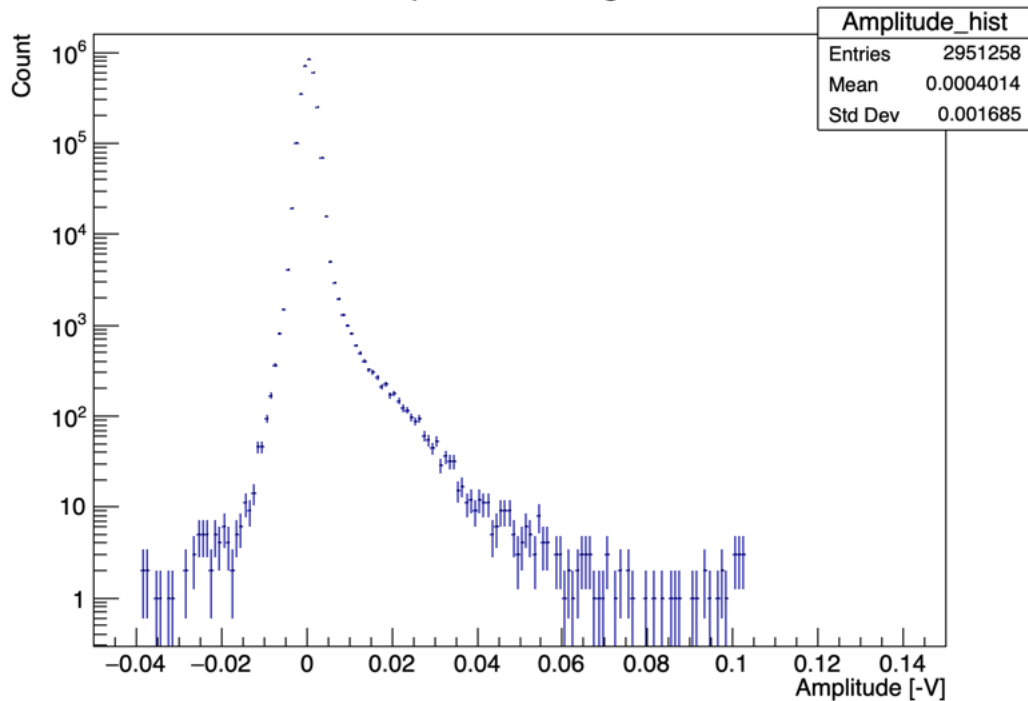
Trigger: -150mV PMT signal



Trigger dependence; Bias Voltage: -185V

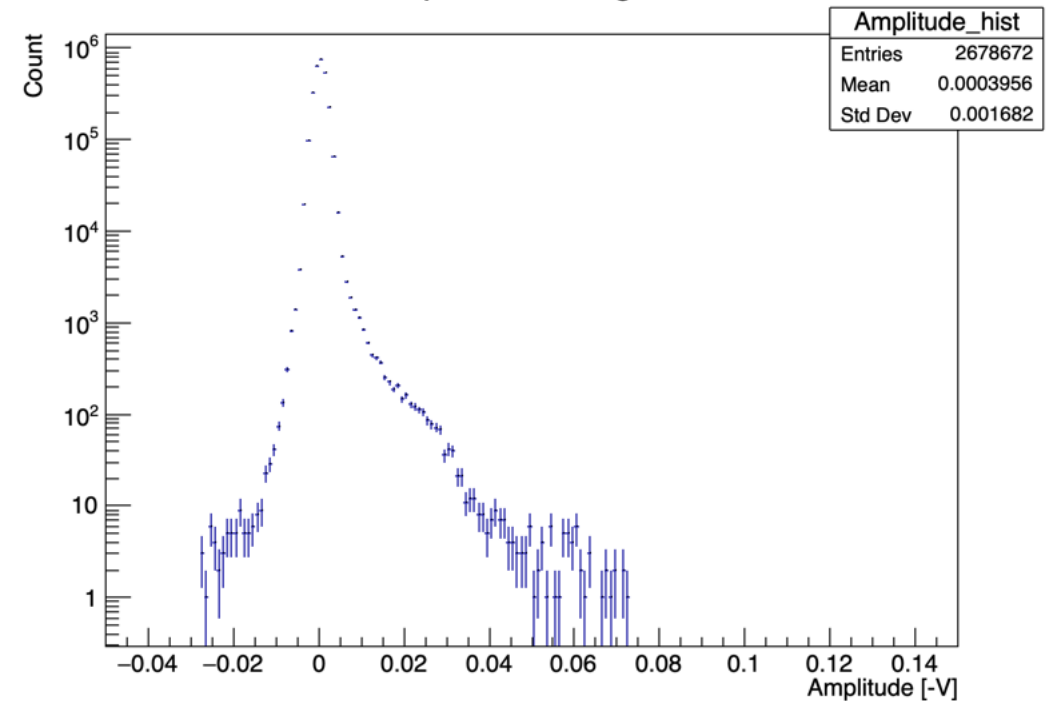
Trigger: -200mV PMT signal

Amplitude Histogram



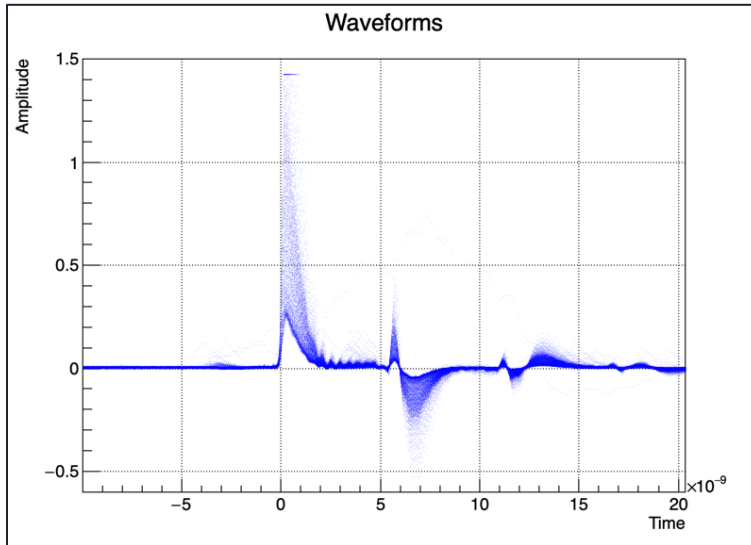
Trigger: -250mV PMT signal

Amplitude Histogram



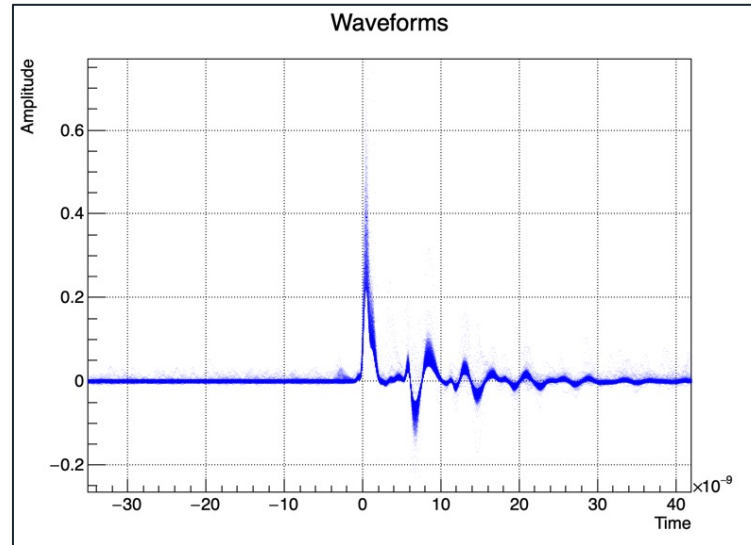
6/11 -4300V Trigger:-150mV

none



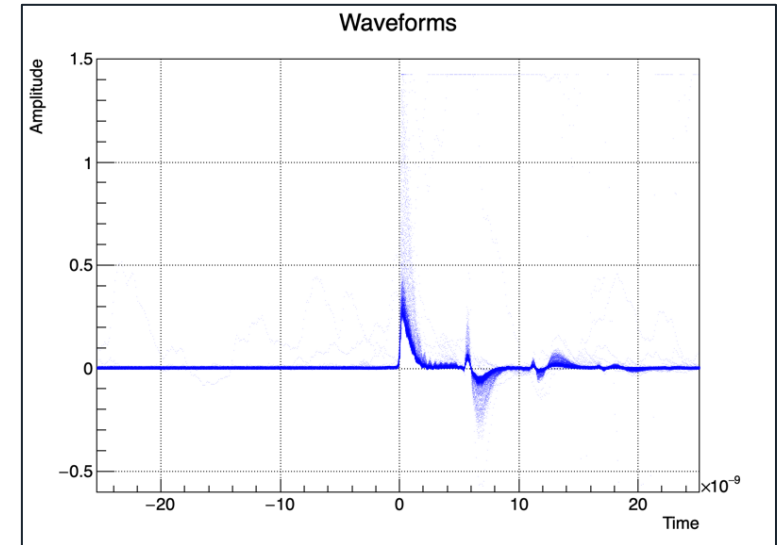
900 events, 4329s
0.2 Hz

Sr-90 only



1024 events, 54s
19 Hz

Sr-90 + AC-LGAD

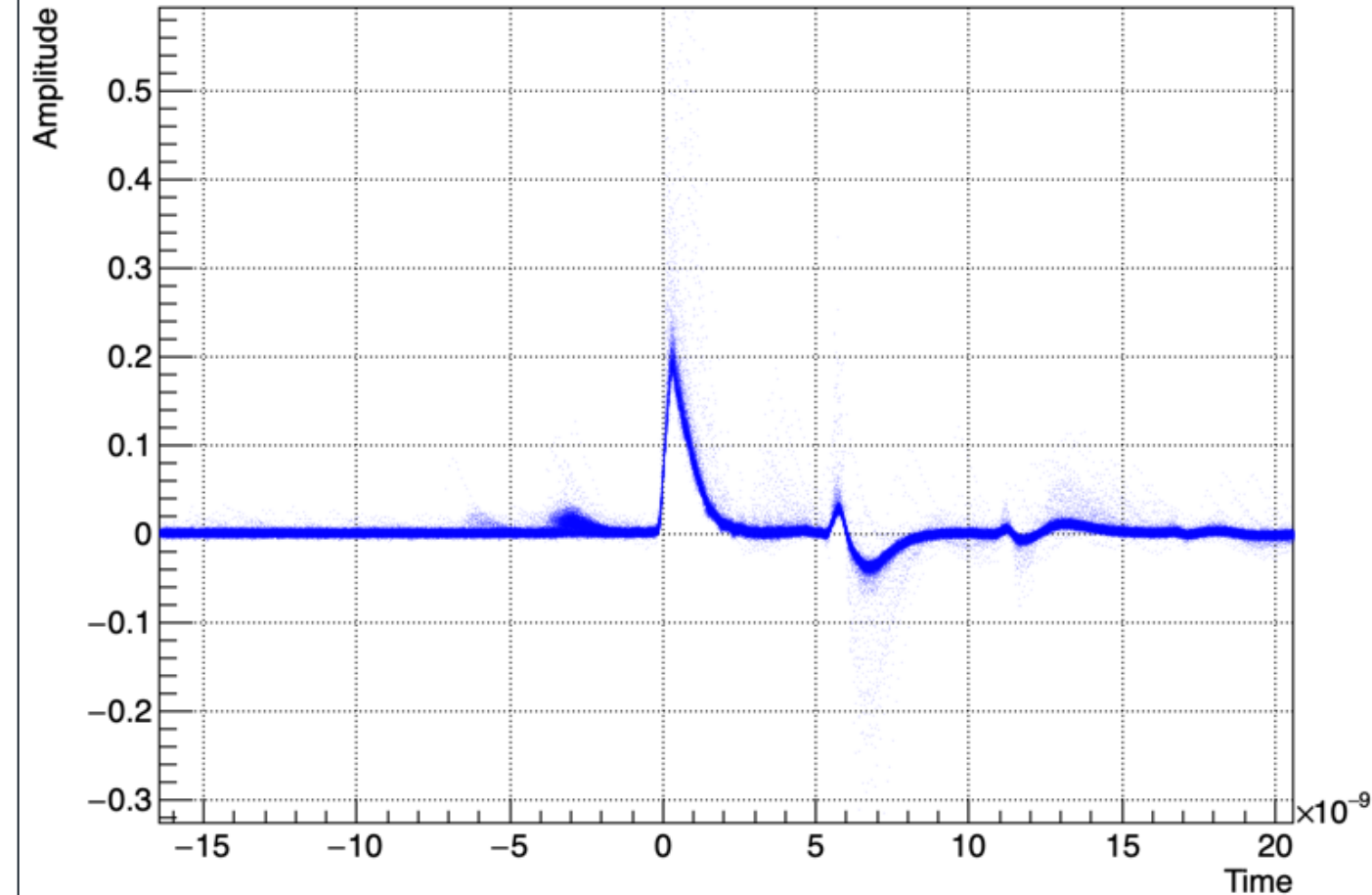


1005 events, 813s
1.2 Hz

Threshold : Signalの50%が-150mVを超えた時を0sとする
→そもそものSignalが-300mV以上でないと反応しない
→検出回数が少ない原因？

6/11 -4300V Trigger: -75 mV

Waveforms



Sr-90 + AC-LGAD

**1138 events, 195s
5.8 Hz**

やはり(当たり前だが) Triggerが低いと
検出効率は上がる

AC-LGADのSignalを見て, どちらも逃
がさないかつNoiseの少ないtriggerを探
す

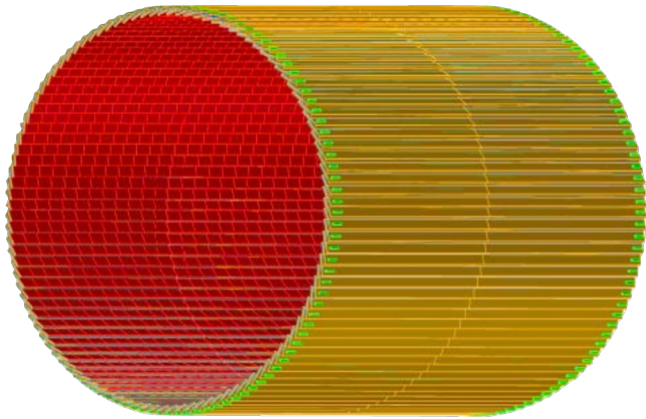
オシロスコープでできたこと

- Waveformの拡大
 - ✓ 見たいところ, 測定したいところを細かく見る
- MeasureモードでAmpl., Rise time, jitterの計算などをみる
 - ✓ それぞれの平均最大最小 σ などいろいろ見ることができる
 - ✓ 計算は四則演算, 逆数など簡単なもの (組み合わせ可)
- ThresholdをTime walkの影響をなくす50% Trigger Signalに設定
 - ✓ 信号のブレがあきらかに減った
- 統計を貯めてHist表示
 - ✓ 例えば, Rise timeの時間分布, ampl.のブレを見たりできる。
- PMTとAC-LGADの信号の到達時間差を計算してヒスト表示もできそう

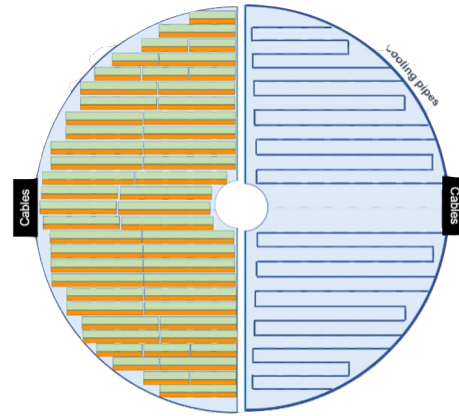
Background: AC-LGAD application at EIC

Improve spatial, similar time resolution to previous incarnation (AC-LGAD) various applications at EIC

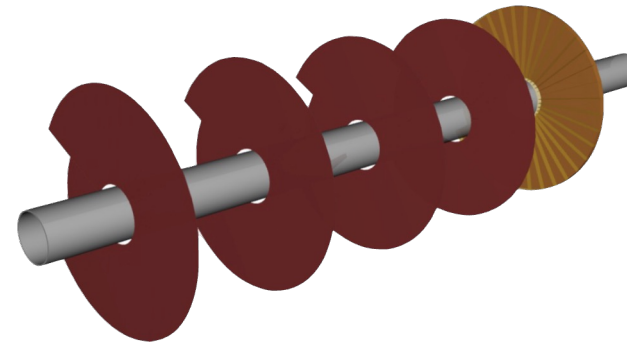
Barrel TOF (strips)



Forward TOF (pixel)



B0 tracker
(pixel)



Roman/OMD (pixel)



	Area (m ²)	Channel size (mm ²)	# of Channels	Timing Resolution	Spatial resolution	Material budget
Barrel TOF	10	0.5*10	2.4M	30 ps	30 μm in $r \cdot \varphi$	0.01 X0
Forward TOF	2	0.5*0.5	8.8M	25 ps	30 μm in x and y	0.05 X0
B0 tracker	0.07	0.5*0.5	0.28M	30 ps	20 μm in x and y	0.01 X0
RPs/OMD	0.14/0.08	0.5*0.5	0.56M/0.32M	30 ps	140 μm in x and y	no strict req.

AC-LGAD devices has the [potential to enhance EIC detectors' capabilities in a significant way](#), with eRD112 and eRD109 groups spearheading the R&D of this technology

Open areas for generic R&D: [ASIC compatibility of long-strip sensor, large area sensor production](#)